

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of

Simon DELEONIBUS

10/546009

Application No.: New
PCT/FR04/000467

U.S. National

Stage

of DT09 Rec'd PCT/PTO 18 AUG 2005

Filed: August 18, 2005

Docket No.: 125073

For: METHOD FOR DELINEATING A CONDUCTING ELEMENT DISPOSED ON AN
INSULATING LAYER, DEVICE AND TRANSISTOR THUS OBTAINEDINFORMATION DISCLOSURE STATEMENTCommissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

Pursuant to 37 CFR §1.56, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached PTO-1449. Unless otherwise indicated herein, one copy of each reference is attached. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

- ☒ 1. This Information Disclosure Statement is being filed (a) within three months of the U.S. filing date of this non-CPA application, OR (b) before the mailing date of a first Office Action on the merits in the present application. No certification or fee is required.
- ☒ 2. Relevance of the non-English language reference 6 is discussed in the present specification.
- ☒ 3. The references 1-4, 6 and 7 were cited in a counterpart foreign application. An English language version of the foreign search report is attached for the Examiner's information.
- ☒ 4. The references 1, 2, 5 and 6 were cited in the International Search Report. An English language version of the International Search Report is attached for the Examiner's information.
- ☒ 5. In accordance with 37 CFR §1.98(a)(2)(ii), copies of any U.S. patents and patent application publications are not attached.
- ☒ 6. An English language Abstract of the non-English language reference 6 is attached hereto.
- ☒ 7. A computer-generated English language translation of the Japanese Patent Publication 6 has been obtained from the website of the Japanese Patent Office (<http://www.jpo.go.jp>), and is attached, but has not been reviewed for accuracy.

Respectfully submitted,

William P. Berridge
Registration No. 30,024Eric D. Morehouse
Registration No. 38,565

WPB:EDM/cqc

Date: August 18, 2005

OLIFF & BERRIDGE, PLC
P.O. Box 19928
Alexandria, Virginia 22320
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Form PTO-1449 (REV. 8-83)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 125073		APPLICATION NO. New U.S. National Stage of PCT/EP04/000467 107546009	
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				APPLICANT Simon DELEONIBUS			
				FILING DATE August 18, 2005			
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	
	1)	US 6,451,657 B1	09/17/2002	GARDNER et al.			
	2)	US 2001/0020723 A1	09/13/2001	GARDNER et al.			
	3)	4,666,556	05/19/1987	FULTON et al.			
	4)	3,867,148	02/18/1975	O'KEEFFE et al.			
	5)	US 6,331,490 B1	12/18/2001	STEVENS et al.			
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	
	6)	JP A 2002-134544 w/ abst. & trans	05/10/2002	JAPAN			
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)							
	7)	"Defect-free Si in Regrown Simox Structures," Vol. 35, No. 3, pp. 60-61, August 1992					
EXAMINER				DATE CONSIDERED			
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Date: August 18, 2005